

# Micro Signal Type Tester

## II. TH2683A/B Insulation Resistance Meter

### Features

- Test voltage range: 1-1000V(TH2683A)  
1-500V(TH2683B)
- Insulation resistance test range: 100KΩ-10TΩ
- Insulation resistance, leakage current dual display
- 24-bits, 4.3-inch and 4-wire touch LCD screen
- LCD resolution: 480\*272
- Zero clearing function
- Contact detection function for capacitive components
- Fast test: 30ms
- Programmable sequence test mode
- 6 ranges, manual or auto range mode
- 4-bin comparison function: 3 bins for PASS, 1 bin for FAIL
- 20 setup files can be stored in the internal memory, support U-disk
- Measurement data can be stored on U-disk
- Automatically upgrade firmware by a disk
- Selectable Chinese and English operation interfaces
- Handler interface realizes on-line operation
- Achieve remote control by RS232C and USB Device interface
- Footswitch trigger function



RS232	USB HOST	USB DEVICE	HANDLER
standard	standard	standard	standard

### TH2683A/B

Rack mount (mm): 215(W)×88(H)×335(D)  
Dimension (mm): 235(W)×105(H)×360(D)  
Weight: 3.6kg

### Application

- Ultra-High Value Resistors
- Insulation resistance and leakage current of capacitors
- Various dielectric insulating materials, equipment, wires and cables
- Insulation testing from safety regulations

### Specifications

Model	TH2683A	TH2683B
Resistance test		
Test range	100kΩ-10TΩ	100kΩ-5TΩ
Test accuracy	I>10nA :±2% I≤10nA :±5%	
Current test		
Test range	Range 1: 100uA - 1mA, internal input impedance 10kΩ Range 2: 10uA - 100uA, internal input impedance 10kΩ Range 3: 1uA - 10uA, internal input impedance 10kΩ Range 4: 100nA - 1uA, internal input impedance 10kΩ Range 5: 10nA - 100nA, internal input impedance 1MΩ Range 6: 1nA - 10nA, internal input impedance 1MΩ	
Test accuracy	2%±3pA	
Test voltage		
Range	1V-1000V	1V-500V
Accuracy	Voltage≥10V: 1%±1V Voltage<10V: 10%±0.1V	
Current limit	10mA	
ON/OFF	Manually turn on or off it on front panel, or controlled by built-in timer, or by remote control	
Charge time	0-999s programmable	
Measurement delay	0-999s programmable	
Measurement speed	Fast: single measurement time≤30ms; Slow: single measurement time≤60ms	
Comparator function	4 bins: 3 bins for PASS, 1 bin for FAIL	
Range mode	Auto, Hold	
Memory	Internal memory and external USB disk	